

## United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/772,447	02/06/2004	Takeo Shiba	NITT.0185	5163		
7	7590 10/30/2006			EXAMINER		
Reed Smith LLP			HON, SO	HON, SOW FUN		
Suite 1400 3110 Fairview Park Drive		ART UNIT	PAPER NUMBER			
Falls Church, VA 22042-4503			1772			
		DATE MAILED: 10/30/2006				

Please find below and/or attached an Office communication concerning this application or proceeding.

## **Advisory Action**

Application No.	Applicant(s)	
10/772,447	SHIBA ET AL.	
Examiner	Art Unit	0
Sow-Fun Hon	1772	

Defere the Eiling of an Anneal Priof			
Before the Filing of an Appeal Brief	Examiner	Art Unit	
	Sow-Fun Hon	1772	<u> </u>
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence add	ress
THE REPLY FILED 16 October 2006 FAILS TO PLACE THIS A	APPLICATION IN CONDITION FOR	RALLOWANCE.	:
<ol> <li>The reply was filed after a final rejection, but prior to or on this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a No a Request for Continued Examination (RCE) in compliance time periods:</li> <li>The period for reply expires 3 months from the mailing date b)</li> </ol>	wing replies: (1) an amendment, aff tice of Appeal (with appeal fee) in one ce with 37 CFR 1.114. The reply more of the final rejection.	idavit, or other evider compliance with 37 C ust be filed within one	nce, which FR 41.31; or (3) of the following
no event, however, will the statutory period for reply expire to Examiner Note: If box 1 is checked, check either box (a) or TWO MONTHS OF THE FINAL REJECTION. See MPEP 7	ater than SIX MONTHS from the mailing (b). ONLY CHECK BOX (b) WHEN THE	g date of the final rejecti	on.
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of ex under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	on which the petition under 37 CFR 1.1 tension and the corresponding amount shortened statutory period for reply orig r than three months after the mailing da	of the fee. The appropri inally set in the final Offi	ate extension fee ce action; or (2) as
<ol> <li>The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exte a Notice of Appeal has been filed, any reply must be filed AMENDMENTS</li> </ol>	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	is of the date of e appeal. Since
3. ☑ The proposed amendment(s) filed after a final rejection,  (a) ☑ They raise new issues that would require further co  (b) ☐ They raise the issue of new matter (see NOTE belo	nsideration and/or search (see NO		ecause
<ul> <li>(c) ☐ They are not deemed to place the application in beauppeal; and/or</li> <li>(d) ☒ They present additional claims without canceling a</li> </ul>			the issues for
NOTE: (See 37 CFR 1.116 and 41.33(a)).			
<ul> <li>4.  The amendments are not in compliance with 37 CFR 1.1</li> <li>5.  Applicant's reply has overcome the following rejection(s)</li> </ul>	:		-
6. Newly proposed or amended claim(s) would be all non-allowable claim(s).			:
7.  For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is pro The status of the claim(s) is (or will be) as follows: Claim(s) allowed: <u>None</u> . Claim(s) objected to: <u>None</u> . Claim(s) rejected: <u>1-25</u> . Claim(s) withdrawn from consideration: <u>None</u> .		ii be entered and an e	xpianation of
<ul> <li>AFFIDAVIT OR OTHER EVIDENCE</li> <li>8. ☐ The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good an</li> </ul>	it before or on the date of filing a N	otice of Appeal will <u>no</u>	t be entered
was not earlier presented. See 37 CFR 1.116(e).			:
<ol> <li>The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to a showing a good and sufficient reasons why it is necessar</li> <li>The affidavit or other evidence is entered. An explanation</li> </ol>	overcome <u>all</u> rejections under appe y and was not earlier presented. S	al and/or appellant fa ee 37 CFR 41.33(d)(	ils to provide a 1).
REQUEST FOR RECONSIDERATION/OTHER  11. The request for reconsideration has been considered by			
———	it does from place the application in	11 CONTRACTOR LINGWAY	ioo boodagoo.
<ul> <li>12. ☐ Note the attached Information Disclosure Statement(s).</li> <li>13. ☐ Other: <u>Attachment to advisory action</u>.</li> </ul>	(PTO/SB/08) Paper No(s)		:
·			

Art Unit: 1772

## **Advisory Action**

- 1. The proposed amendment dated 10/16/06 will not be entered because it raises new issues that would require further consideration and search, and presents additional new claims 26-28 without canceling a corresponding number of finally rejected claims.
- 2. Applicant's arguments in pages 6-8 of Applicant's remarks, are directed against the new limitation of "each having only a drain electrode connected to a corresponding one of the phase-change device elements", which is part of the proposed amendment that has not been entered. Hence said arguments are not addressed in this advisory action.
- 3. Applicant argues that because Kurokawa provides a frame memory utilizing electrically erasable and programmable read only memory (EEPROM) having floating gates, Shindo discloses a solar battery having a p-I-n structure utilizing a single-crystalline Si substrate or a memory cell including a TFT, and a method of manufacturing such a solar battery or memory, and Ovshinsky provides a phase change memory for an optical disk, [that these references are non-analogous art] and hence a mere combination of said three references would produce a configuration of an image display device different in structure, type, function and application that the image display device recited in the independent claims of the invention.

Applicant is respectfully apprised that Kurokawa is the primary reference that teaches an image display device (column 18, lines 65-66) comprising a nonvolatile memory device having a memory comprised of transistors (memory transistor, column 17, lines 53-55, plurality of transistors, column 3, line 39), and that Shindo is the

Art Unit: 1772

secondary device relied upon as evidence that while Kurokawa fails to disclose that these memory transistors are thin films, transistors in the form of thin films are well known in the art, and that thin film transistors are used as part of a nonvolatile memory device (column 133, lines 1-18) for the purpose of utilizing the physical properties of the thin films. Shindo teaches a semiconductor device which can be either a solar cell or a nonvolatile memory (column 1, lines 9-20), and which uses thin film transistors (memory cells formed by thin film transistors, column 133, lines 1-2), wherein the nonvolatile memory is utilized in an EPROM or a flash EPROM (column 180, lines 18-26). The EEPROM of Kurokawa is a species of the EPROM, and can be a flash type (memory, column 5, lines 64-66). Thus, Shindo and Kurokawa are both directed to a nonvolatile memory utilized in an EPROM or flash EPROM, and are analogous art.

Regarding the validity of Ovshinsky, Ovshinsky is the secondary reference that teaches that the reversible amorphous to crystalline phase change of semiconductor materials (column 5, lines 12-16) is used in nonvolatile memory devices for the purpose of providing high-speed, low-energy, direct-overwrite and grey-scale operation (column 21, lines 25-45), which approaches the nonvolatility and random access programming capabilities of an EEPROM (column 40, lines 51-58). Kurokawa teaches a semiconductor nonvolatile memory (abstract). Ovshinsky teaches a semiconductor nonvolatile memory (column 1, lines 1-18). Thus, all three references are directed to a semiconductor nonvolatile memory, and are analogous art. Therefore, a combination of Kurokawa, Shindo and Ovshinsky does produce a configuration of an image display device that meets the image display device recited in the present claims.

Art Unit: 1772

4. Applicant argues regarding claims 7 and 18, that Ovshinsky merely discloses that "repeatable and detectable switching resistance values can be effected", and that this statement does not teach or suggest the configuration of the present invention in which the variable-resistance memory element is free from variations in resistance value due to registration errors of masks.

Applicant is respectfully apprised that in using the term "repeatable" to describe the switching resistance values, Ovshinsky teaches that there are no variations in resistance values due to errors, wherein registration errors of masks are but a subset of the errors. Hence, Ovshinsky does indirectly teach that the variable-resistance memory element is free from variations in resistance value due to registration errors of masks.

5. Applicant argues regarding claim 10, that Kurokawa's frame memory disclosed is configured to store data corresponding to each of the pixels, while Applicant's invention uses each of the plurality of pixels itself to store corresponding data therein, wherein the display having pixel memories is completely different in structure, type and function from that of Kurokawa.

Applicant is respectfully apprised that the pixel memory and the structure of the pixel memory are not recited in the present claims. Kurokawa teaches that the image signal is stored in the nonvolatile memory to be inputted into the pixel portion to be displayed (column 19, lines 39-44), that there is a plurality of pixels (column 19, lines 36-40), and that there is a plurality of memory transistors (column 3, line 39), wherein the total memory capacity is equal to at least the number of the pixels X 6 bits (column 19, lines 39-44), thus implying that each of said plurality of pixels has a function which

Art Unit: 1772

Page 5

retains display data therein, a feature which is well-known in the art, as evidenced by US 4,875,190 and US 4,668,568.

Any inquiry concerning this communication should be directed to Sow-Fun Hon whose telephone number is (571)272-1492. The examiner can normally be reached Monday to Friday from 10:00 AM to 6:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Harold Pyon, can be reached at (571)272-1498. The fax phone number for the organization where this application or proceeding is assigned is (571)273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Sow-Fun Hon

0/25/06

HENA DYE SUPERVISORY PATENT EXAMINER

Technology Center 1755